TMA4275 LIFETIME ANALYSIS

Slides 6: Nelson-Aalen estimator, exponential distribution, TTT-plot, logrank test

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CONTENTS OF SLIDES 6

- Nonparametric estimation of *Z*(*t*): The Nelson-Aalen estimator
 - Motivation from KM-estimator
 - Motivation from "scratch" using exponential distribution
- Properties of the exponential distribution
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 - Property of transformations etc
 - Z(T) is exponentially distributed
 - The homogeneous Poisson-process
- Total time on test (TTT)
 - TTT-plot, uncensored data
 - TTT-plot, right censored data
- Barlow-Proschan's test for exponentiality
- Nonparametric comparison of reliability/survival functions
 - The logrank test

Note first that Z'(t) = z(t). Thus,

- T is IFR $\Leftrightarrow z(t)$ is increasing $\Leftrightarrow Z(t)$ is convex
- T is DFR $\Leftrightarrow z(t)$ is decreasing $\Leftrightarrow Z(t)$ is concave

Thus a plot of an estimate $\hat{Z}(t)$ can give us information on whether the distribution of T is IFR (*increasing failure rate*) or DFR (*decreasing failure rate*).

ESTIMATING Z(t) BY THE KM-ESTIMATOR

Recall that $R(t) = e^{-Z(t)}$, so

 $Z(t) = -\ln R(t)$

Thus, if $\hat{R}_{KM}(t)$ is the KM-estimator for R(t), then we can define,

$$egin{aligned} \hat{Z}_{\mathcal{KM}}(t) &= -\ln \hat{R}_{\mathcal{KM}}(t) \ &= -\ln \prod_{\mathcal{T}_{(i)} \leq t} rac{n_i - d_i}{n_i} \ &= -\sum_{\mathcal{T}_{(i)} \leq t} \ln \left(1 - rac{d_i}{n_i}
ight) \ &pprox \sum_{\mathcal{T}_{(i)} \leq t} rac{d_i}{n_i} \end{aligned}$$

where we used that for small x is

$$-\ln(1-x)\approx x$$

THE NELSON-AALEN ESTIMATOR FOR Z(t)

The Nelson-Aalen estimator (NA-estimator) is simply defined by

$$\hat{Z}_{NA}(t) = \sum_{T_{(i)} \leq t} rac{d_i}{n_i}$$

It can then be shown that its variance can be estimated by

$$\widehat{Var(\hat{Z}_{NA}(t))} = \sum_{T_{(i)} \leq t} \frac{d_i}{n_i^2}$$

Note: The Nelson-Aalen estimator is *not* included in MINITAB (only "hazard plot" which is in fact not correct). For this course has been made a *MINITAB Macro* (see MINITAB Macros on the Software webpage).

In the following we shall have a closer look at how the Nelson-Aalen estimator can be motivated from properties of the exponential distribution.

EXAMPLE: NELSON-AALEN ESTIMATOR

Row	C1	C2						
1	31,7	1						
2	39,2	1						
3	57,5	1						
4	65,0	0						
5	65,8	1						
6	70,0	1						
7	75,0	0						
8	75,2	0						
9	87,5	0	Row	Time	Numb at risk	1/Numb at risk	Cum Haz Nelson	Survival Nelson
10	88,3	0						
11	94.2	0	1	31,7	16	0,062500	0,06250	0,939413
10	101 7	0	2	39,2	15	0,066667	0,12917	0,878827
12	101,7	v	3	57,5	14	0,071429	0,20060	0,818244
13	105,8	1	4	65,8	12	0,083333	0,28393	0,752820
14	109.2	0	5	70,0	11	0,090909	0,37484	0,687401
15	110.0	1	6	105,8	4	0,250000	0,62484	0,535348
16	130.0	0	7	110,0	2	0,500000	1,12484	0,324705

Nelson Plot



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Slides 6

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GENERAL THEORY: RESIDUAL LIFETIME

Suppose an item with lifetime T is still alive at time s. The probability of surviving an additional t time is then

$$R(t \mid s) \equiv P(T > s + t \mid T > s)$$

$$= \frac{P(T > s + t \cap T > s)}{P(T > s)}$$

$$= \frac{R(s + t)}{R(s)}$$

This is called the *conditional survival function* of the item, or *the distribution of the residual life for an item at age s*. The following is its expectation, called *Mean Residual Life:*

$$MRL(s) = \int_0^\infty R(t \mid s) dt = \int_0^\infty \frac{R(s+t)}{R(s)} dt$$
$$= \frac{1}{R(s)} \int_s^\infty R(t) dt$$

1. The memoryless property

Write
$$T \sim \operatorname{expon}(\lambda)$$
 if $f(t) = \lambda e^{-\lambda t}$; $R(t) = P(T > t) = e^{-\lambda t}$, $t > 0$.

For $T \sim expon(\lambda)$ we therefore have

$$R(t \mid s) = P(T > s+t \mid T > s) = rac{R(s+t)}{R(s)} = rac{e^{-\lambda(s+t)}}{e^{-\lambda s}} = e^{-\lambda t} = R(t).$$

Thus: For any age s, the remaining life has the same distribution as the lifetime distribution of a new item.

This is called **the memoryless property** of the exponential distribution.

Let T ~ expon(λ) and let W = aT. Then W ~ expon(λ/a).
 Proof:

$$P(W > w) = P(aT > w) = P(T > \frac{w}{a}) = e^{-(\frac{\lambda}{a})w}$$

3. Let T_i for i = 1, ..., n be independent, with $T_i \sim \operatorname{expon}(\lambda_i)$. Let $W = \min(T_1, ..., T_n)$. Then $W \sim \operatorname{expon}(\sum_{i=1}^n \lambda_i)$. *Proof:*

$$P(W > w) = P(\min(T_1, \dots, T_n) > w)$$

= $P(T_1 > w, T_2 > w, \dots, T_n > w)$
= $P(T_1 > w)P(T_2 > w) \dots P(T_n > w)$
= $e^{-(\lambda_1 + \dots + \lambda_n)w}$,

so $W \sim \operatorname{expon}(\lambda_1 + \cdots + \lambda_n)$

4. In particular if T_1, \ldots, T_n are independent each with distribution expon(λ), then

$$W = \min(T_1, \ldots, T_n) \sim \exp(n\lambda)$$

So a series system of n components with lifetimes that are independent and exponentially distributed with hazard rate λ , has a lifetime which is exponenital with hazard rate $n\lambda$ and hence

$$\mathsf{MTTF} = \frac{1}{n\lambda} = \frac{\mathsf{Component MTTF}}{n}$$

5. Let T_1, \ldots, T_n be independent each with distribution expon(λ). Let the ordering of these be

$$T_{(1)} < T_{(2)} < \cdots < T_{(n)}$$

Then

$$nT_{(1)}$$

$$(n-1)(T_{(2)} - T_{(1)})$$

$$(n-2)(T_{(3)} - T_{(2)})$$

$$\vdots$$

$$(n-i+1)(T_{(i)} - T_{(i-1)})$$

$$\vdots$$

$$(T_{(n)} - T_{(n-1)})$$

are independent and identically distributed as $expon(\lambda)$.

5b. Let T_1, \ldots, T_n be independent each with distribution $expon(\lambda)$. Let the ordering of these be

$$T_{(1)} < T_{(2)} < \cdots < T_{(n)}$$

Then

$$T_{(1)} \sim \exp(n\lambda)$$

$$T_{(2)} - T_{(1)} \sim \exp((n-1)\lambda)$$

$$T_{(3)} - T_{(2)} \sim \exp((n-2)\lambda)$$

$$\vdots$$

$$T_{(i)} - T_{(i-1)} \sim \exp((n-i+1)\lambda)$$

$$\vdots$$

$$T_{(n)} - T_{(n-1)} \sim \exp(\lambda)$$

are independent with the displayed exponential distributions.

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Proof of 5b: Let n units with lifetime $expon(\lambda)$ be put on test at time 0. Hence $T_{(1)} = \min(T_1, \ldots, T_n)$, so by property 4, $T_{(1)} \sim expon(n\lambda)$. After time $T_{(1)}$ there are n-1 unfailed units. At time $s = T_{(1)}$ each of these has by property 1 a remaining lifetime which is $expon(\lambda)$. Thus $T_{(2)} - T_{(1)}$ is distributed as the minimum of $n-1 expon(\lambda)$ variables and hence is $expon((n-1)\lambda)$. That $T_{(2)} - T_{(1)}$ is independent of $T_{(1)}$ follows from property 1 which says that, for the exponential distribution, the distribution of the remaining lifetime is the same whatever be the age of the item.

This reasoning can be continued at time $T_{(2)}$ in an obvious fashion, and we finish by concluding that $T_{(n)} - T_{(n-1)}$ is $expon(\lambda)$.

Proof of 5: To go from 5b to 5, we use the earlier property 2.

Consider lifetime T with given cumulative hazard function Z(t). After we observe T, we may compute Z(T), which is hence a random variable since T is a random variable. The following result says that this random variable is exponentially distributed with parameter 1, whatever be the distribution of T. The important point is of course that it is T's own Z(t) that is used to transform T.

Proof: Recall that $Z(t) = -\ln R(t)$ and R(t) = P(T > t). Thus we have:

$$P(Z(T) > z) = P(-\ln R(T) > z) = P(\ln R(T) < -z)$$

= $P(R(T) < e^{-z}) = P(T > R^{-1}(e^{-z}))$
= $R(R^{-1}(e^{-z})) = e^{-z}$

so $Z(T) \sim \exp(1)$. Here we used that R(t) is decreasing and hence has a decreasing inverse function R^{-1} .

EXAMPLES

- Suppose T ~ expon(λ). Then z(t) = λ and Z(t) = λt. Thus the result says that Z(T) = λT ~ expon(1). But this also follows from the previous Property 2 for the exponential distribution.
- Suppose then $T \sim \text{Weibull}(\alpha, \theta)$, so that $Z(t) = \left(\frac{t}{\theta}\right)^{\alpha}$. Then

$$Z(T) = \left(\frac{T}{\theta}\right)^{\theta}$$

so

$$P(Z(T) > z) = P(\left(\frac{T}{\theta}\right)^{\alpha} > z) = P\left(\frac{T}{\theta} > z^{1/\alpha}\right)$$
$$= P(T > \theta z^{1/\alpha}) = R(\theta z^{1/\alpha})$$
$$= e^{-\left(\frac{\theta z^{1/\alpha}}{\theta}\right)^{\alpha}} = e^{-z}$$

i.e. $Z(T) \sim expon(1)$.

INTERPRETATION OF $Z(T) \sim expon(1)$

Write the result as

$$Z(T) = \int_0^T z(u) du = V$$

where $V \sim \exp(1)$.

If we think of V as "given" to us at birth, drawn from an expon(1)-distribution, then our lifetime T is determined by the behavior of the hazard function z(t). Thus the lifetime will be longer if we are able to reduce our hazard throughout life.

The result can also be used to simulate lifetimes T_1, \ldots, T_n for a sample of units: Draw independent expon(1)-variables V_1, \ldots, V_n and compute the corresponding T_i as

$$T_i = Z^{-1}(V_i), i = 1, ..., n$$

NELSON-AALEN PLOT: NONCENSORED DATA

Suppose data are *n* independent observations T_1, \ldots, T_n of the lifetime *T* with cumulative hazard function Z(t), with no censored observations.

Then $Z(T_1), \ldots, Z(T_n)$ are i.i.d. expon(1), and from figure:



Nelson: For noncensored data, estimate the function Z(t) by letting

$$\hat{Z}(T_{(i)}) = \frac{1}{n} + \frac{1}{n-1} + \dots + \frac{1}{n-i+1}$$
 for $i = 1, 2, \dots, n$

(and let $\hat{Z}(t)$ be constant between observations).

NELSON-AALEN PLOT: CENSORED DATA

Let $T_{(1)} < T_{(2)} < \cdots$ be the observed *failure* times.

Assume that the censored observations are always deleted from the data in the immediate beginning of each interval $(T_{(i-1)}, T_{(i)})$, and let n_i be the number at risk after deletion of the censored ones.



Nelson-Aalen: Estimate the function Z(t) by letting

$$\hat{Z}(T_{(i)}) = \frac{1}{n_1} + \frac{1}{n_2} + \dots + \frac{1}{n_i}$$
 for $i = 1, 2, \dots$

(and let $\hat{Z}(t)$ be constant between observations).

TOTAL TIME ON TEST, T(t)

n components are put on test at time t = 0 and observed until failure.

Let $\mathcal{T}(t) = Total Time on Test$ at time t.



Recall:

• *n* components are put on test at time t = 0 and observed until failure.

•
$$\mathcal{T}(t) = Total Time on Test at time t.$$

A non-normalized TTT-plot would be a plot of the points

$$(i, \mathcal{T}(T_{(i)})), i = 1, \cdots, n.$$

The convention is, however, to plot the points

$$\left(\frac{i}{n}, \frac{\mathcal{T}(\mathcal{T}_{(i)})}{\mathcal{T}(\mathcal{T}_{(n)})}\right)$$
 or $\left(\frac{i}{n}, \frac{Y_i}{Y_n}\right)$, for $i = 1, 2, \dots, n$

The last point is thus (1,1), so this plot is always in the unit square.

TTT-PLOT, UNCENSORED DATA



Recall definition of TTT-plot: Plot the points

$$\left(\frac{i}{n},\frac{Y_i}{Y_n}\right)$$
 for $i=1,2,\ldots,n$,

where $Y_i = \mathcal{T}(T_{(i)})$ is total time on test until $T_{(i)}$.

n = 10; uncensored observations $T_{(1)}, \ldots, T_{(10)}$.

Row	Time	TTT interval	TTT cum	i/n	TTT
1	6,3	10*6,3 = 63,0	63,0	0,1	0,05943
2	11,0	9*4,7 = 42,3	105,3	0,2	0,09934
3	21,5	8*10,5 = 84,0	189,3	0,3	0,17858
4	48,4	7*27,9 = 188,3	377, <mark>6</mark>	0,4	0,35623
5	90,1	6*41,7 = 250,2	627,8	0,5	0,59226
6	120,2	5*30,1 = 150,5	778,3	0,6	0,73425
7	163,0	4*42,8 = 171,2	949, <mark>5</mark>	0,7	0,89575
8	182,5	3*19,5 = 58,5	1008,0	0,8	0,95094
9	198,0	2*15,5 = 31,0	1039,0	0,9	0,98019
10	219,0	1*21,0 = 21,0	1060,0	1,0	1,00000

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EXAMPLE: TTT-plot

TTT plot



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WHAT ARE TTT-PLOTS USED FOR?



Recall that if T_1, \ldots, T_n are expon (λ) , then

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$$(n-i+1)(T_{(i)}-T_{(i-1)})\sim \operatorname{expon}(\lambda),$$

SO

$$E(Y_i) = E(\mathcal{T}(T_{(i)})) = i(1/\lambda) = i/\lambda$$
 for $i = 1, ..., n$

SO

$$E\left(\frac{Y_i}{Y_n}\right) \approx \frac{i/\lambda}{n/\lambda} = \frac{i}{n}$$

so the TTT-plot is approximately a plot of (i/n, i/n) which are on the diagonal of the square defined by the TTT-plot.

DIAGNOSTICS FROM TTT-PLOTS



- IFR: *Concave shape.* The first lifetimes are generally longer than expected from an exponential distribution, while the last ones are shorter.
- DFR: *Convex shape*. The first lifetimes are generally shorter than expected from an exponential distribution, while the last ones are longer.

Bathtub: *S-shaped*, i.e. convex (DFR) in the beginning and concave (IFR) at the end.

TTT: BALL-BEARING DATA

BALL BEARINGS FAILURE DATA



TTT plot

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Definition: Let N(s, t) = number of events in(s, t]

$$P(N(t,t+h)=1) = \lambda h + o(h) \approx \lambda h$$

$$P(N(t,t+h) \geq 2) = o(h) \approx 0$$

For disjoint intervals (s₁, t₁], (s₂, t₂],..., the counts N(s₁, t₁], N(s₂, t₂],... are independent random variables.

It can be shown that:

•
$$N(s,t)$$
 is Poisson $(\lambda(t-s))$ so $E[N(s,t)] = \lambda(t-s)$

 λ is called the *intensity* of the process.

HPP: TIME TO kth EVENT



- Times between events are independent and distributed as $expon(\lambda)$.
- The time to the kth event (k = 1, 2, ...) is gamma-distributed with pdf and reliability function given by, respectively,

$$f(t) = rac{\lambda(\lambda t)^{k-1}e^{-\lambda t}}{(k-1)!}$$
 for $t > 0$

$$R(t) = P(S_k > t) =_{(*)} P(N(t) \le k - 1) = \sum_{x=0}^{k-1} \frac{(\lambda t)^x}{x!} e^{-\lambda t}$$

(*) See time point *t* in figure.

MORE ON THE HOMOGENEOUS POISSON PROCESS

RESULT 1:



Let the HPP start at time t = 0 and continue until a given number n events have occurred. Then, given the value $S_n = s_n$, the event times S_1, \ldots, S_{n-1} are distributed as the ordering of n - 1 i.i.d. variables from the distribution $U[0, s_n]$, i.e. the uniform distribution on the interval from 0 to s_n .

MORE ON THE HOMOGENEOUS POISSON PROCESS

RESULT 2:



Let the HPP start at time t = 0 and continue until a given time τ . Let N denote the number of events that have occurred until time τ (this is a random number). Then, given the value N = n, the event times S_1, \ldots, S_n are distributed as the ordering of n i.i.d. variables from the distribution $U[0, \tau]$, i.e. the uniform distribution on the interval from 0 to τ .

TTT-PLOT FOR EXPONENTIAL OBSERVATIONS



Suppose T_1, \ldots, T_n are distributed as expon(λ). Then Y_1, Y_2, \ldots behaves like an HPP with intensity λ (called HPP(λ)), by result 5. By Result 1:

- Given the value $Y_n = y_n$, the (Y_1, \ldots, Y_{n-1}) are distributed as the ordering of n-1 i.i.d. $U[0, y_n]$.
- Hence, given the value $Y_n = y_n$, the $(Y_1/y_n, \ldots, Y_{n-1}/y_n)$ are distributed as the ordering of n-1 i.i.d. U[0, 1].
- Since the latter distribution does not depend on y_n , the $(Y_1/Y_n, \ldots, Y_{n-1}/Y_n)$ are distributed as the ordering of n-1 i.i.d. U[0,1].

TTT-PLOT FOR EXPONENTIAL OBSERVATIONS



Recall: The $\left(\frac{Y_1}{Y_n}, \ldots, \frac{Y_{n-1}}{Y_n}\right)$ are distributed as the ordering of n-1 i.i.d. U[0,1].

From this can be shown that we have, under exponentiality, exactly:

$$E\left(\frac{Y_i}{Y_n}\right) = \frac{i}{n}, \text{ for } i = 1, \dots, n-1$$

(we concluded only \approx earlier).

One is often not satisfied with just looking at *plots* to determine distributions. Assume we want to formally test

Suppose T_1, \dots, T_n is complete data set, i.e. no censorings.

The test statistic of Barlow-Proschan's test is

$$W = \frac{Y_1}{Y_n} + \frac{Y_2}{Y_n} + \dots + \frac{Y_{n-1}}{Y_n} = \frac{\mathcal{T}(\mathcal{T}_{(1)})}{\mathcal{T}(\mathcal{T}_{(n)})} + \dots + \frac{\mathcal{T}(\mathcal{T}_{(n-1)})}{\mathcal{T}(\mathcal{T}_{(n)})}$$



When compared to the exponential distribution:

- W becomes "too large" if distribution is IFR
- W becomes "too small" if distribution is DFR

Thus: The null hypothesis H_0 of exponential distributon should be *rejected* if W is either much larger or much smaller than what should be expected from exponentially distributed lifetimes.

We therefore need the distribution of W when $T_1, \ldots, T_n \sim expon(\lambda)$. We know already:

$$\frac{Y_1}{Y_n}, \cdots, \frac{Y_{n-1}}{Y_n}$$

are distributed as the ordering of n-1 independent U[0,1]-variables, so:

• W = sum of n-1 independent U[0,1]-variables

•
$$E(W) = (n-1)/2$$

•
$$Var(W) = (n-1)/12$$

Thus by the Central Limit Theorem, W is approximately normal:

$$W pprox N(rac{n-1}{2},rac{n-1}{12})$$
 when lifetimes are exponential

Recall:

$$W = \frac{Y_1}{Y_n} + \frac{Y_2}{Y_n} + \dots + \frac{Y_{n-1}}{Y_n} \approx N(\frac{n-1}{2}, \frac{n-1}{12})$$

Thus we compute

$$Z = \frac{W - \frac{n-1}{2}}{\sqrt{\frac{n-1}{12}}}$$

which is $\approx N(0, 1)$ under H_0 .

Tests with level α : Let T_1, \dots, T_n be a complete sample of T.

 H_0 : $T \sim expon(\lambda)$

versus
$$H_1: \begin{cases} T \text{ is IFR} : \text{Reject if } Z \ge z_{\alpha} \\ T \text{ is DFR: Reject if } Z \le -z_{\alpha} \\ T \text{ has monotone hazard: Reject if } Z \le -z_{\alpha/2} \text{ or } Z \ge z_{\alpha/2} \end{cases}$$

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CRITICAL VALUES OF NORMAL DISTRIBUTION

TABLE 4 Critical Values of Standard Normal Distribution

A ONE-TAILED SITUATIONS

The entries in this table are the critical values for z for which the area under the curve representing α is in the right-hand tail. Critical values for the left-hand tail are found by symmetry.

				Am	ount of a	x in one	tail
α	0.25	0.10	0.05	0.025	0.02	0.01	0.005
$z \alpha\rangle$	0.67	1.28	1.65	1.96	2.05	2.33	2.58



 α = area of one tail

 α

B TWO-TAILED SITUATIONS

The entries in this table are the critical values for z for which the area under the curve representing α is split equally between the two tails.



			tails						
α	0.25	0.20	0.10	0.05	0.02	0.01	Two-tailed example: $\alpha = 0.05 \text{ or } 1 - \alpha = 0.95$		
$z[\alpha/2]$	1.15	1.28	1.65	1.96	2.33	2.58	$\alpha/2 = 0.025$		
$1 - \alpha$	0.75	0.80	0.90	0.95	0.98	0.99	$z(\alpha/2) = z(0.025) = 1.96$		
Area in the "center"									
E 15	1.1.1.1		W11 A.4	5 1			444		

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EXAMPLE: BARLOW-PROSCHAN'S TEST

Row	Time	TTT interval	TTT cum	i/n	TTT
1	6,3	10*6,3 = 63,	0 63,0	0,1	0,05943
2	11,0	9*4,7 = 42,	3 105,3	0,2	0,09934
3	21,5	8*10,5 = 84,	0 189,3	0,3	0,17858
4	48,4	7*27,9 = 188,	3 377,6	0,4	0,35623
5	90,1	6*41,7 = 250,	2 627,8	0,5	0,59226
6	120,2	5*30,1 = 150,	5 778,3	0,6	0,73425
7	163,0	4*42,8 = 171,	2 949,5	0,7	0,89575
8	182,5	3*19,5 = 58,	5 1008,0	0,8	0,95094
9	198,0	2*15,5 = 31,	0 1039,0	0,9	0,98019
10	219,0	1*21,0 = 21,	0 1060,0	1,0	1,00000

Here W is the sum of the last column, except the last "1". We have W = 4.847 and

$$Z = \frac{4.847 - \frac{9}{2}}{\sqrt{\frac{9}{12}}} = 0.401$$

so we do not reject at $\alpha = 0.05$, for example.

Image: A mathematical states and a mathem

EXAMPLE OF BP TEST: BALL-BEARING DATA

BALL BEARINGS FAILURE DATA



Use of Macro from course web page: W = 15.648, n = 23, so

$$Z = \frac{15.648 - 11}{\sqrt{\frac{22}{12}}} = 3.4328$$

and we reject (at any reasonable significance level) a test of

 H_0 : exponential distribution versus H_1 : IFR distribution,

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TTT-PLOT FOR CENSORED DATA



Let $T_{(1)} < T_{(2)} < \cdots < T_{(k)}$ be the observed *failure* times.

Assume that the censored observations are always deleted from the data in the immediate beginning of each interval $(T_{(i-1)}, T_{(i)})$, and let n_i be the number at risk after deletion of the censored ones.

Then Y_1, Y_2, \ldots is still a HPP when lifetimes are exponential.

On the previous slide, the censored observations contribute to the Total Time on Test only in the intervals strictly before the ones where they are censored.

An improvement of the method is to let the censored observations contribute also in the interval where they are censored, but only up to the time they are censored.

This means in practice that we compute the TTT as for the noncensored case, but we let *only the* **failure times** *be recorded as the event times* Y_1, \ldots, Y_k , and we plot

$$\left(rac{i}{k},rac{Y_i}{Y_k}
ight), ext{ for } i=1,\ldots,k$$

EXAMPLE: TTT-PLOT FOR CENSORED DATA

Row	Time	Censor No	at risk	Total time	Cum total time	Plot total time
1	31,7	1	16	507,2	507,2	507,2
2	39,2	1	15	112,5	619,7	619,7
3	57,5	1	14	256,2	875,9	875,9
4	65,0	0	13	97,5	973,4	983,0
5	65,8	1	12	9,6	983,0	1029,2
6	70,0	1	11	46,2	1029,2	1274,3
7	75,0	0	10	50,0	1079,2	1286,1
8	75,2	0	9	1,8	1081,0	
9	87,5	0	8	98,4	1179,4	
10	88,3	0	7	5,6	1185,0	
11	94,2	0	6	35,4	1220,4	
12	101,7	0	5	37,5	1257,9	
13	105,8	1	4	16,4	1274,3	
14	109,2	0	3	10,2	1284,5	
15	110,0	1	2	1,6	1286,1	
16	130,0	0	1	20,0	1306,1	
Row	i/r	n TTI				
1	0,14286	6 0,39437	' Da	ta from Tabl	e 11.1/9.3	
2	0,28571	0,48184	BA BA	RLOW-PROSCHA	N'S TEST:	
3	0,42857	0,68105	5			
4	0,57143	0,76433	3			
5	0,71429	0,80025	5 W	= 0.39+0.48+	0.68+0.76+0.80+0	.99 =
6	0,85714	0,99082	2	= 4.10 (k-1 = 6)	
7	1.00000	1.00000)			

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EXAMPLE: TTT-PLOT FOR CENSORED DATA

TTT-plot censored data



Assume first two groups:

Group 1: Control group, lifetime T_1 , with $R_1(t) = P(T_1 > t)$ Group 2: Treatment group, lifetime T_2 , with $R_2(t) = P(T_2 > t)$

Want to test:

$$H_0: R_1(t) = R_2(t)$$
 for all t

(i.e. no difference between groups)

vs $H_1: R_1(t) \neq R_2(t)$ for at least one t

Graphical solution: Look at KM-Plots

EXAMPLE: LEUKEMIA DATA

Comparing two groups:

6-Mercaptopurine in Acute Leukemia

The 6-Mercaptopurine in Acute Leukemia trial

- Conducted in 1959-1960
- Patients had undergone corticosteroid therapy for acute leukemia
- 6-Mercaptopurine versus placebo
- Outcome: length of complete remission (weeks)
- Subjects entered in pairs and followed until at least one member of each pair relapsed.
- Stopped after 21 pairs of subjects were entered

Outcomes ("+"=censored):

- 6-MP: 6+, 6, 6, 6, 7, 9+, 10+, 10, 11+, 13, 16, 17+, 19+, 20+, 22, 23, 25+, 32+, 32+, 34+, 35+
- Placebo: 1, 1, 2, 2, 3, 4, 4, 5, 5, 8, 8, 8, 8, 11, 11, 12, 12, 15, 17, 22, 23

EXAMPLE: LEUKEMIA DATA

Group 1=Placebo (control), Group 2=6MP



EXAMPLE: LEUKEMIA DATA

Group 1=Placebo (control), Group 2=6MP (with 95% confidence intervals)



FORMAL TESTING OF H_0 : $R_1(t) \equiv R_2(t)$

Formal testing can be done by

- The Logrank Test
- Mantel-Haenszel Test

A simple version is to compute a $\chi^2\mbox{-statistic}$ of the form

$$V = \frac{(O_1 - E_1)^2}{E_1} + \frac{(O_2 - E_2)^2}{E_2}$$

where

- O_1, O_2 are *observed* # failures of the two groups
- E_1, E_2 are expected # failures if the survival functions are equal.
- Note that $O_1 + O_2 = \text{total number of failures} = E_1 + E_2$.

Under H_0 is $V \approx \chi_1^2$ (i.e. χ^2 -distributed with 1 degree of freedom)

COMPUTATION

Go through all failure times $T_{(1)}, \dots, T_{(k)}$ considering groups together:

	Group 1	Group 2	Total at $T_{(j)}$
# at risk:	N_{1j}	N_{2j}	Nj
Obs # fail at $T_{(i)}$	O_{1j}	O_{2j}	O_j
Est prob of fail under H_0	$\frac{O_j}{N_j}$	$\frac{O_j}{N_j}$	
Estim exp $\#$ failures	$E_{1j} = rac{O_j}{N_j} \cdot N_{1j}$	$E_{2j} = rac{O_j}{N_j} \cdot N_{2j}$	

Then sum over all failure times $T_{(1)}, \dots, T_{(k)}$:

$$O_1 = \sum_{j=1}^k O_{1j}, \ E_1 = \sum_{j=1}^k E_{1j}$$

 $O_2 = \sum_{j=1}^k O_{2j}, \ E_2 = \sum_{j=1}^k E_{2j}$

If more than two groups are compared, the table and the test statistic are extended in a natural way, while the degrees of freedom of the χ^2 -distribution equals # groups minus 1.

LOGRANK TEST FOR LEUKEMIA DATA

C = Control group (Placebo)

B = Treatment group (6MP)

Time	RiskC	RiskB	Risk	FailC	FailB	Fail	EC		EB	
1 2 3 4	21 19 17 16	21 21 21 21 21	42 40 38 37	2 2 1 2	0 0 0 0	2 2 1 2	(2/42) *21 (2/40) *19 (1/38) *17 (2/37) *16	= 1 = 0.95 = 0.447 = 0.865	(2/42) *21 (2/40) *21 (1/38) *21 (2/37) *21	= 1 = 1.05 = 0.553 = 1.135
13	4	12	16	0	1	1	(1/16) *4	= 0.25	(1/16) *12	= 0.75
23	1	6	7	1	1	2	(2/7) *1	= 0.286	(2/7) *6	= 1.714
Total	L			21	9			10.749		19.251

Test statistic:

$$\frac{(O_C - E_C)^2}{E_C} + \frac{(O_B - E_B)^2}{E_B}$$
$$= \frac{(21 - 10.749)^2}{10.749} + \frac{(9 - 19.251)^2}{19.251} = 5.46 + 9.77 = 15.33$$

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